Electrical & Computer ENGINEERING

SEMINAR

JOINTLY PRESENTED BY CSSI AND ECE SEMINAR SERIES

THURSDAY
FEBRUARY 17, 2004

Scaife Hall Auditorium
Room 125

4:00 PM
Refreshments—3:30 PM

ADAPTIVE COMPUTING: HOW TO TEST?

Adaptive Computing is one of the high tech buzzwords these days. What is adaptive computing (from a testing perspective)? Is it really brand new? What would it change (in the test landscape)?

The presenter will show part of the history as well as the new faces of adaptive computing. He will show how this new product feature will bring changes to the test industry.

TM Mak
INTEL CORPORATION

TM Mak is a Senior Staff engineer with Intel Corporation's Design Technology Group, carrying out test research and development. He has been with Intel for 20 years and has worked on a variety of areas including test development, product engineering, design automation and design for test. He has served as mentor to the test research with the SRC and GSRC (GigaScale Silicon/System Research Center). He twice (1997 and 2004) received the SRC Outstanding Industrial Mentor Award. His current research interest ranges from defect based testing, fault effects as a result of nanometer technology, circuit level and physical design test issues, IO interface and analog testing, fault tolerant and on-line testing. He received the best paper award in 2003 International Test Conference. He currently holds 6 patents with 6 more pending. He has served on the program committees of various conference and workshops. He is a Senior Member of IEEE and a graduate from Hong Kong Polytechnic University.

Shawn Blanton and James C. Hoe,
Seminar Hosts
blanton@ece.cmu.edu
jhoe@ece.cmu.edu

For more information:
http://www.ece.cmu.edu/seminar

Carnegie Mellon
Electrical & Computer ENGINEERING

CSSI